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3.22 Mechanical Properties of Materials
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Multidimensional Defects in III-V Semiconductors

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[1] Image by Andy Kim; <http://sauvignon.mit.edu>

"Cross-sectional TEM image of $\text{InGa}(1-x)\text{P}/\text{GaP}$ compositionally graded buffer."

Big Picture: III-V Devices

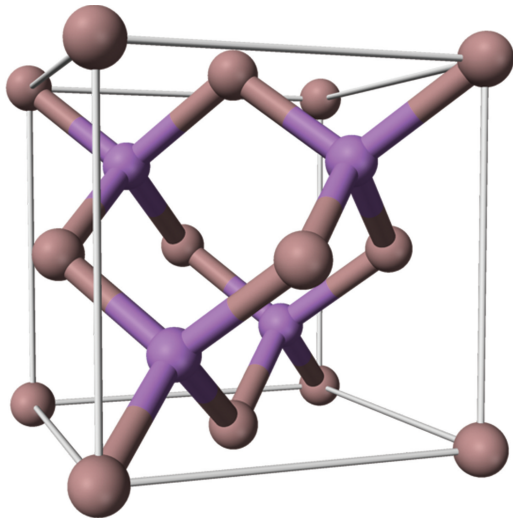
- Applications: high speed electronics, optical (GaAs: red; GaN: blue; green?)
- Mechanical properties:
 - Substrate handling
 - Avoid delamination
- Importance of defects:
 - Point defects: electronic properties
 - Line defects:
 - electronic properties
 - mechanical properties
 - Temperature effect
 - processing
 - during device operation
 - Avoid in active region
- Thin films: graded buffers often used
 - Avoid dislocations in substrate

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http://www-opto.e-technik.uni-ulm.de/lehre/cs/III_V_map_a.jpg

Microscopic mechanism

GaAs thin films:

- Anisotropy of the stiffness tensor:
Crystal structure, 3 independent constants
- Thickness dependence of K_{IC} :
Nanoindentation : mixed mode loading.
Thin film: insufficient thickness
- Interaction matrix



[1]

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[1] Wikimedia Commons, <http://commons.wikimedia.org>

[2] <http://www-vrl.umich.edu/project2/miller/index.htm>

[3] Hjort, Klas, Jan Soderkvist, and Jan-Ake Schweitz. "Gallium arsenide as a mechanical material." *Journal of Micromechanics and Microengineering* 4 (1994): 1-13.

Prediction & Optimization

- Prediction:
 - Growth of thin films along $\langle 111 \rangle$ direction
 - Thickness beyond which K_{IC} is constant.
- Optimization
 - Strong substrate for ease of handling
 - Inherent difficulty: 2+ element basis
 - Graded buffers: threading dislocations glide to wafer edge

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Please see Fig. 1 and 3a in [3].